

Automatic data processing based on the skewness statistic parameter for subsurface defect ...

Automatic data processing based on the skewness statistic parameter for subsurface defect detection by active infrared thermography

F.J. Madruga, C. Ibarra-Castanedo, O.M. Conde, J.M. Lázquez-Higuera, X. Maldague

Quirt2008, Krakow, Poland, pp. 1-6; 02/07/2008